

# Modeling DDR3 with IBIS Randy Wolff, Micron Technology

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# **DDR3** Requirements

- Clock speeds of 400-800(+) MHz, Data rates of 800-1600(+) Mb/s
- Improvements to model accuracy needed
  - Include accurate package models
  - Properly model On-Die Termination
  - Describe V-t curves within appropriate time window
- Additions to IBIS specification



# Package Models

- FBGA packages simulated with 3D Field Solver
- Custom script converts output RLC matrices to IBIS format
  - Needed to convert net names into ball names (DQ1 to A1, VSS to B1, etc.)
  - RLC matrix must then be sorted by ball ID
- Input capacitance correlated between simulation and measurement using a VNA
- Accuracy decreases if package includes on-die signal/power bussing



### 1Gb x8 DDR3 Input C Correlation

#### **Cin comparison**



### Package Models - Power supply terminal reduction

- Usually, the simulation setup used in 3D analysis is merged sinks on ball side of the package and separated sources on die pad locations.
- For IBIS modeling, multiple die terminals (sources) are not allowed
- 3D analysis completed with the following setups:
  - Regular die pads as sources, balls as sinks (merged)
  - Reverse sink die pads sinks (merged), balls as sources
  - Merged all die pads as sources (merged), balls as sinks (merged)
- Frequency Domain comparison



### **Results (DQ0 Characteristics)**



#### Transmission

Reflection

### **Results (VDDQ Transmission Characteristics)**



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### Results (DQ0-VDDQ Coupling)

#### Far End

#### Near End



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### **Results (VSSQ Transmission Characteristics)**



### Results (DQ0-VSSQ Coupling)

#### Far End

Near End



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# Package Modeling Conclusions

- The three setups give very similar results up to ~1GHz
- High frequency effects are more prominent in a setup with more terminals because a model with greater number of mutual terms represents the system better.
- Merging sources and/or sinks results in sufficient accuracy



### **On-Die Termination Modeling**

- ODT model improved with recommendations from Bob Ross' presentation "Extracting On-Die Terminators" - DesignCon East 2005
- Old methodology used Clip-and-Extend
- New methodology correctly models ODT structure for proper power supply referencing





### **Combined Clamp Curves**



File: u48b\_bd.ibs, Model: 75ohm\_ODT\_533 (GND + POWER Clamps)

### **Power Clamp**

### **Ground Clamp**



### **Combined Clamp Curves**



File: v48a.ibs, Model: 60ohm\_ODT\_1067 (GND + POWER Clamps)

### **Power Clamp**

### **Ground Clamp**



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# V-t Curve Time Shifting

- V-t curve time window for DDR3-1333 is 750ps
- Typical V-t curve extraction (correlated across slow/typ/fast to the same clock stimulus) requires ~950ps to capture all corner cases
- 950ps reduces effective data rate to 1050 Mbps
- Time shifting all typical and minimum waveforms by t<sub>shift</sub>(typ) and t<sub>shift</sub>(min) reduces time window to 750ps
- To correlate with original SPICE model, IBIS stimulus is delayed by t<sub>shift</sub>(typ) or t<sub>shift</sub>(min)



### V-t Curve Time Shifting

#### Original model with 950ps time window

### Time Shifted model with 750ps time window



# **DDR3 IBIS Spec Improvements**

- IBISCHK 4.2 parser adoption
  - Fixes [Receiver Thresholds] differential measurement issues
- Lossy C\_comp needed to improve correlation to SPICE and measurements
- Additions needed to the IBIS specification for DDR3 timing measurements
  - Slew rate derating
  - t<sub>VAC</sub>



### DDR3 t<sub>VAC</sub> and Slew Rate Derating



#### Required time t<sub>VAC</sub> above VIH(ac) {below VIL(ac)} for valid transition

Slew Rate [V/ns]	t <sub>VAC</sub> [ps]				
	min	max			
> 2.0	75	-			
2.0	57	-			
1.5	50	-			
1.0	38	-			
0.9	34	-			
0.8	29	-			
0.7	22	-			
0.6	13	-			
0.5	0	-			
< 0.5	0	-			

	ΔtDS, ΔDH derating in [ps] AC/DC based <sup>1</sup>																	
		DQS, DQS# Differential Slew Rate																
		4.0	4.0 V/ns		3.0 V/ns		2.0 V/ns		1.8 V/ns		1.6 V/ns		1.4 V/ns		1.2 V/ns		1.0 V/ns	
		∆tDS	∆tDH	∆tDS	∆tDH	∆tDS	∆tDH	∆tDS	∆tDH	∆tDS	∆tDH	∆tDS	∆tDH	∆tDS	∆tDH	∆tDS	∆tDH	
DQ Slew rate V/ns	2.0	88	50	88	50	88	50	-	-	-	-	-	-	-	-	-	-	
	1.5	59	34	59	34	59	34	67	42	-	-	-	-	-	-	-	-	
	1.0	0	0	0	0	0	0	8	8	16	16	-	-	-	-	-	-	
	0.9	-	-	-2	-4	-2	-4	6	4	14	12	22	20	-	-	-	-	
	0.8	-	-	-	-	-6	-10	2	-2	10	6	18	14	26	24	-	-	
	0.7	-	-	-	-	-	-	-3	-8	5	0	13	8	21	18	29	34	
	0.6	-	-	-	-	-	-	-	-	-1	-10	7	-2	15	8	23	24	
	0.5	-	-	-	-	-	-	-	-	-	-	-11	-16	-2	-6	5	10	
	0.4	-	-	-	-	-	-	-	-	-	-	-	-	-30	-26	-22	-10	

# Modeling DDR3 with IBIS

- Comments?
- Questions?

